
**Non-destructive testing — Ultrasonic
testing — Examination for discontinuities
perpendicular to the surface**

*Essais non destructifs — Contrôle par ultrasons — Contrôle des
discontinuités perpendiculaires à la surface*

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Published in Switzerland

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Foreword

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

International Standards are drafted in accordance with the rules given in the ISO/IEC Directives, Part 2.

The main task of technical committees is to prepare International Standards. Draft International Standards adopted by the technical committees are circulated to the member bodies for voting. Publication as an International Standard requires approval by at least 75 % of the member bodies casting a vote.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. ISO shall not be held responsible for identifying any or all such patent rights.

ISO 16826 was prepared by Technical Committee ISO/TC 135, *Non-destructive testing*, Subcommittee SC 3, *Ultrasonic testing*.

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Introduction

This International Standard is based on EN 583-4:2002+A1:2003, *Non-destructive testing — Ultrasonic examination — Part 4: Examination for discontinuities perpendicular to the surface*.

The following International Standards are linked.

ISO 16810, *Non-destructive testing — Ultrasonic testing — General principles*

ISO 16811, *Non-destructive testing — Ultrasonic testing — Sensitivity and range setting*

ISO 16823, *Non-destructive testing — Ultrasonic testing — Transmission technique*

ISO 16826, *Non-destructive testing — Ultrasonic testing — Examination for discontinuities perpendicular to the surface*

ISO 16827, *Non-destructive testing — Ultrasonic testing — Characterization and sizing of discontinuities*

ISO 16828, *Non-destructive testing — Ultrasonic testing — Time-of-flight diffraction technique as a method for detection and sizing of discontinuities*

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Non-destructive testing — Ultrasonic testing — Examination for discontinuities perpendicular to the surface

1 Scope

This International Standard defines the principles for tandem- and longitudinal-longitudinal-transverse (LLT) wave examination for the detection of discontinuities perpendicular to the surface.

The general principles required for the ultrasonic examination of industrial products are described in ISO 16810. A list of symbols and equations is given in ISO 16811.

The tandem- or LLT-examination should be used for the detection of planar discontinuities with distance to the surface greater than 15 mm. This International Standard has been prepared for the examination of metallic materials with a thickness between 40 mm and 500 mm with parallel or concentric surfaces. It can, however, be used for other materials and smaller thickness provided special measures are taken.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

ISO 5577, *Non-destructive testing — Ultrasonic inspection — Vocabulary*

ISO 16810, *Non-destructive testing — Ultrasonic testing — General principles*

ISO 16811, *Non-destructive testing — Ultrasonic testing — Sensitivity and range setting*

EN 1330-4, *Non-destructive testing — Terminology — Terms used in ultrasonic testing*

3 Terms and definitions

For the purposes of this document, the terms and definitions given in ISO 5577 and EN 1330-4 apply.

4 Tandem examination

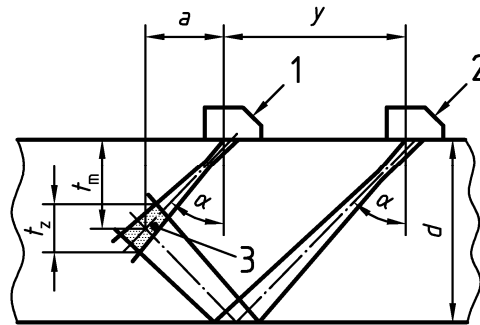
4.1 General

The examination is normally carried out using two similar 45° angle probes, one probe operating as the transmitter and the other probe as receiver. For wall thicknesses greater than approximately 160 mm, probes with different transducer sizes are preferred in order to ensure approximately the same beam diameters in the examination zone.

The use of probe angles other than 45° may be necessary to comply with particular geometrical conditions. Probe angles that give rise to mode conversions shall be avoided.

The probes are located in a line with their acoustic axis in the same direction. In this way the sound beam from the rear probe will, after reflection from the opposite surface, intersect the sound beam from the front probe at the centre of the examination zone.

Figure 1 shows the relationship between the spacing of the probes (y) and the examination depth of the crosspoint (t_m) and the height of the examination zone (t_z).



Key

- | | | | |
|-----|---------------------|-------|----------------------------|
| 1 | Probe 1 | d | Material thickness |
| 2 | Probe 2 | t_m | Examination depth |
| 3 | Examination zone | y | Probe distance |
| a | Projection distance | t_z | Height of examination zone |

Figure 1 — Basic principle of tandem technique
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When examining objects with plane parallel surfaces the distance between the probes can be defined using the following equation:

$$y = 2 \tan \alpha (d - t_m) \tag{1}$$

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for 45°

$$y = 2(d - t_m) \tag{2}$$

Scanning shall be performed in either of the following ways:

- both probes are moved along the surfaces with a fixed distance (y).
 In this way only one examination zone is examined at a time, and the scanning shall be repeated with different probe distance until the complete examination volume has been examined;
- both probes are moved simultaneously, such that the sum of their distances from the required plane of intersection, e.g. the vertical weld axis, remains constant, thereby scanning the full object thickness in one continuous movement.

4.2 Time base adjustment

Basically all relevant echoes will appear at the same sound path distance, which corresponds to the V-path. Therefore, the adjustment of the time base is not important. It is, however, recommended that the echo from the V-path is located at a fixed position e.g. eight scale divisions.

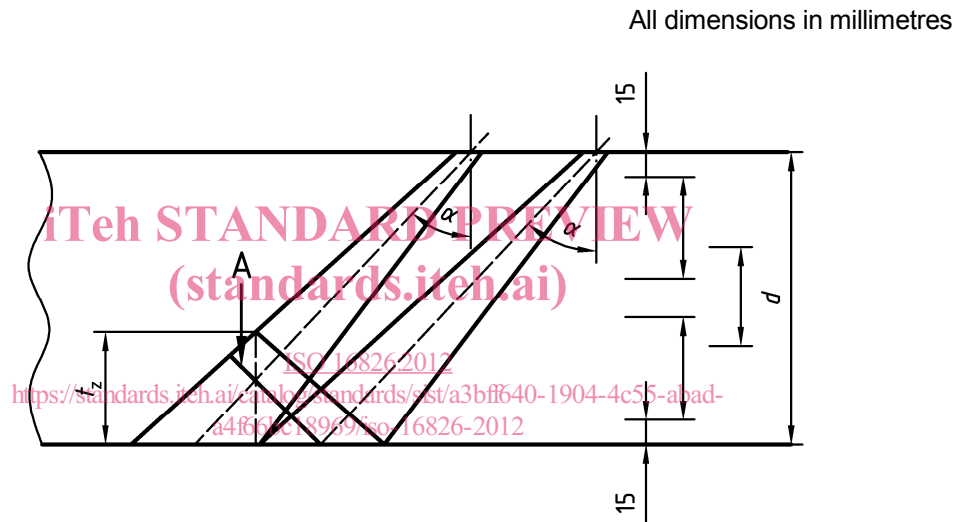
4.3 Setting of sensitivity

The setting of sensitivity can be performed using the following reflectors:

- opposite surface, where the V-path echo is used as backwall echo;
- disk-shaped reflectors perpendicular to the scanning surface (flat-bottomed holes). The reflectors shall be located at the intersection of the beam axes;
- side drilled holes located at the intersection of the beams and at the borders of the examination zones.

4.4 Determination of examination zones

The division into equally sized examination zones ensures that the sensitivity throughout the thickness does not fall below a certain level. The height of the examination zones is calculated so that the sensitivity at the edges of the examination zones is not more than 6 dB below the sensitivity in the intersection point of the beam axes, see Figure 2.



Key

- A Sound beam diameter
 d Material thickness
 t_z Height of examination zone

Figure 2 — Examination zones

The height of the examination zone (t_z) can be determined by using a reference block with reflectors in differentiated depths or calculated as follows based on the diameter of the direct beam and the largest sound path in the examination zone closest to the opposite surface (all dimensions in millimetres):

$$t_z \approx \frac{\lambda(d - 15 \text{ mm})}{\sin \alpha \cdot \cos \alpha \cdot D_{\text{eff}}} \quad (2)$$

for 45°

$$t_z \approx \frac{2 \cdot \lambda \cdot (d - 15 \text{ mm})}{D_{\text{eff}}}$$

where

D_{eff} effective transducer diameter.

The number of examination zones is calculated as follows:

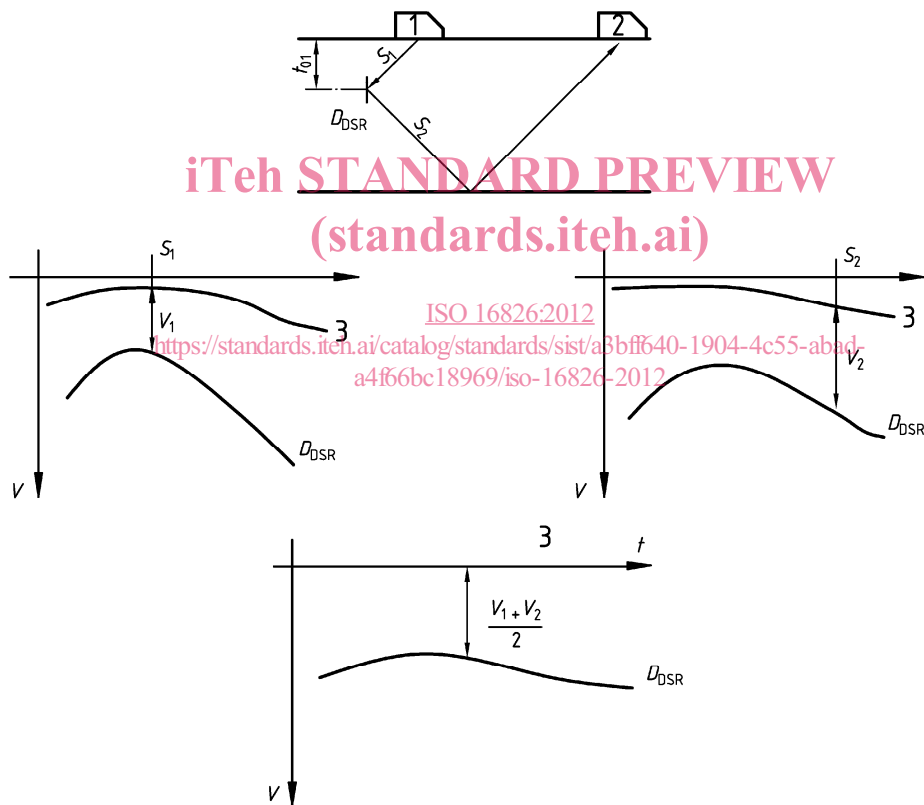
$$n_{tz} = \left\lceil \frac{d - 30 \text{ mm}}{t_z} + 1 \right\rceil, \quad n_{tz} = 1, 2, 3 \tag{3}$$

The probe distance, y , see Figure 1, is adjusted for each examination zone with the intersection of the beam axes in the centre of the zone. Alternatively, the width and number of the examination zones can be determined graphically using scale drawings of the calculated or measured 6 dB beam profiles.

4.5 DGS-diagram for tandem examination

DGS-diagrams for tandem examination may be derived from the general DGS-diagram or based on probe specific diagrams.

The diagrams are prepared as shown in Figure 3. The mean value of the gain differences V_1 and V_2 are derived from the specific diagrams for the probes or from the general DGS diagram. These are used to establish a distance amplitude curve (DAC) for specific tandem examinations, based on this disk-shaped reflector (DSR).



- Key**
- D_{DSR} Disk-shaped reflector
 - S Sound path distance
 - t Depth
 - V Gain
 - 1, 2 Probe 1, probe 2
 - 3 Backwall

Figure 3 — Preparation of tandem DGS-diagram

4.6 Corrections of sensitivity

Depending on the method used for sensitivity setting, corrections for transfer and attenuation losses may be applicable.

In addition to this, compensation shall be made for the reduction of sensitivity that will occur at the edges of the examination zone. Either 6 dB or the value measured on disk-shaped reflectors (flat-bottomed holes) at the border of the examination zones should be used.

4.7 Object with concentric surfaces

The use of 45° angle probes is limited to $d/D \leq 0,04$ for convex scanning surfaces and $d/D \leq 0,05$ for concave scanning surfaces. Where applicable, the angles of incidence shall be changed to prevent mode conversions that can result in reduced sensitivity.

The probe spacing (y) for the examination of such surfaces may be calculated using the equations in 4.7.1 or 4.7.2.

Alternatively, the probe spacing can be determined graphically using scale drawings of the calculated or measured 6 dB beam profiles.

NOTE In Annex A, nomograms are given for the determination of the distances for concave and convex scanning surfaces without calculation.

4.7.1 Concave scanning surface

$$y_1 = \frac{\pi(D-2d)}{360^\circ} \left\{ \alpha - \arcsin \left[\frac{1}{1 + \frac{2t_m}{(D-2d)}} \sin \alpha \right] \right\} \quad (4)$$

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Tandem zone:

$$y_2 = \frac{\pi(D-2d)}{180^\circ} \left\{ \alpha - \arcsin \left[\left(1 - \frac{2d}{D} \right) \sin \alpha \right] \right\} \quad (5)$$

$$y_3 = \frac{\pi(D-2d)}{180^\circ} \left\{ \arcsin \left[\frac{1}{1 + \frac{2t_m}{(D-2d)}} \sin \alpha \right] - \arcsin \left[\left(1 - \frac{2d}{D} \right) \sin \alpha \right] \right\} \quad (6)$$